Amendments to the Claims:

1. (previously presented) A substrate for an unpackaged integrated circuit chip having surface mount contacts disposed thereon in a pattern, comprising:

an insulating material; and

a conductive material disposed over the insulating material, the conductive material comprising a plurality of contacts arranged in a pattern corresponding to the integrated circuit contact pattern, the conductive material comprising a conductive ring disposed around the periphery of the contact pattern, the conductive material comprising a first trace connected to said conductive ring and surrounding a selected one of said plurality of contacts, wherein the substrate contacts are coupleable to the integrated circuit chip surface mount contacts.

- 2. (original) The substrate according to Claim 1, wherein the conductive material comprises at least one conductive trace disposed proximate at least one contact.
- 3. (canceled)
- 4. (original) The substrate according to Claim 1, wherein the substrate contacts comprise wire bond pads, wherein the wire bond pads are coupleable to the integrated circuit chip surface mount contacts.
- 5. (original) The substrate according to Claim 1, wherein the insulating material comprises polyimide, fiberglass or a flexible dielectric material.
- 6. (original) The substrate according to Claim 1, wherein the insulating material includes a plurality of apertures disposed in the integrated circuit contact pattern.
- 7. (original) The substrate according to Claim 1 wherein the conductive material comprises Cu, Pt, Sn, Ni, Ag, Au, Cr, or combinations thereof.

- 8. (original) The substrate according to Claim 1, wherein the conductive material is formed by electro-less plating.
- 9. (previously presented) A package for an integrated circuit chip having surface mount contacts disposed thereon in a pattern, comprising:

a substrate including an insulating material and a conductive material disposed over the insulating material, the conductive material comprising a plurality of contacts arranged in a pattern corresponding to the integrated circuit contact pattern, the conductive material comprising a conductive ring disposed around the periphery of the contact pattern, the conductive material comprising a first trace connected to said conductive ring and surrounding a selected one of said plurality of contacts, wherein the substrate contacts are coupleable to the integrated circuit chip surface mount contacts.

- 10. (original) The package according to Claim 9, wherein the conductive material comprises at least one conductive trace disposed proximate at least one contact.
- 11. (canceled)
- 12. (original) The package according to Claim 9, wherein the substrate contacts comprise wire bond pads, wherein the wire bond pads are coupleable to the integrated circuit chip surface mount contacts.
- 13. (original) The package according to Claim 9, further comprising an encapsulating insulating material disposed over the integrated circuit and substrate.
- 14. (original) The package according to Claim 13, further comprising a shielding material disposed over the encapsulating insulating material, the shielding material being electrically coupled to the conductive material solid ring.

- 15. (original) The package according to Claim 14, wherein the shielding material comprises an electrically conductive material.
- 16. (original) The package according to Claim 14, wherein the shielding material comprises a dissipative material having less than about 1 M Ω resistance.
- 17. (original) The package according to Claim 9, wherein the substrate insulating material comprises polyimide, fiberglass or a flexible dielectric material, and wherein the conductive material comprises Cu, Pt, Sn, Ni, Ag, Au, Cr, or combinations thereof.
- 18. (original) The package according to Claim 9, wherein the substrate insulating material includes a plurality of apertures disposed in the integrated circuit contact pattern.
- 19. (original) The package according to Claim 9, wherein the substrate conductive material is formed by electro-less plating.
- 20. (original) The package according to Claim 9, wherein the integrated circuit comprises a ball grid array, chip scale package, or flip-chip.
- 21. (original) An integrated circuit packaged in the package of Claim 9.

Claims 22-28 (canceled)

29. (previously presented) A packaged integrated circuit, comprising:

a substrate including an insulating material and a conductive material disposed over the insulating material, the conductive material comprising a plurality of contacts, the conductive material further comprising a conductive ring disposed around the periphery of said plurality of contacts, the conductive material further comprising a trace connected to said conductive ring and surrounding a selected one of said plurality of contacts.

- 30. (canceled)
- 31. (previously presented) The packaged integrated circuit of Claim 29, wherein said trace surrounds selected contacts in said plurality of contacts.
- 32. (previously presented) The packaged integrated circuit of Claim 29, wherein said selected one of said plurality of contacts is a controlled impedance connection.
- 33. (previously presented) The packaged integrated circuit of Claim 1, wherein said first trace surrounds selected contacts in said plurality of contacts.
- 34. (previously presented) The packaged integrated circuit of Claim 1, wherein said selected one of said plurality of contacts is a controlled impedance connection.
- 35. (previously presented) The packaged integrated circuit of Claim 9, wherein said first trace surrounds selected contacts in said plurality of contacts.
- 36. (previously presented) The packaged integrated circuit of Claim 9, wherein said selected one of said plurality of contacts is a controlled impedance connection.